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## Key indicators

Single-crystal X-ray study
$T=193 \mathrm{~K}$
Mean $\sigma(\mathrm{C}-\mathrm{C})=0.003 \AA$
$R$ factor $=0.023$
$w R$ factor $=0.049$
Data-to-parameter ratio $=23.9$

For details of how these key indicators were automatically derived from the article, see http://journals.iucr.org/e.
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## $N, N$-Dicyclohexyl-2-iodoacetamide

In the crystal structure of the title compound, $\mathrm{C}_{14} \mathrm{H}_{24} \mathrm{INO}$, the sum of the angles around the N atom is $359.9^{\circ}$, implying a planar configuration.

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## Comment

The title compound, (I), was synthesized in the process of investigating the reactivity of a helical foldamer (Heemstra \& Moore, 2004) with iodoacetamide derivatives. The configuration around the N atom of the acetamide group is essentially planar (sum of angles $=359.9^{\circ}$ ).

(I)

## Experimental

The title compound was prepared by the reaction of 2 -chloro- $\mathrm{N}, \mathrm{N}$ dicyclohexylacetamide (Speziale \& Hamm, 1956a) with 1.2 equivalents of KI in 2-butanone at reflux for 10 h (Speziale \& Hamm, $1956 b$ ). The crude product was washed with brine and was recrystallized from diethyl ether at room temperature. Single crystals suitable for X-ray diffraction were grown at room temperature by evaporation of a diethylether/hexane solution. ${ }^{1}$ H NMR ( 400 MHz , $\mathrm{CDCl}_{3}$ ): $\delta 3.69(s, 2 \mathrm{H}), 3.37(t, J=11.6 \mathrm{~Hz}, 1 \mathrm{H}), 2.88(b r, 1 \mathrm{H}), 2.41(b r$, 2 H ), 1.07-1.86 ( $\mathrm{m}, 18 \mathrm{H}$ ). ${ }^{13} \mathrm{C}$ NMR ( $126 \mathrm{MHz}, \mathrm{CDCl}_{3}$ ): $\delta 166.4,60.1$, $56.3,30.5,26.3,25.7,25.1,25.0,0.0$. MS (EI): $m / z$ (\%): 349 ( $M^{+}, 2.5$ ), 222 (100), 168 (14.0), 140 (62.0), 98 (25.6), 83 (31.2), 55 (68.0). HRMS calculated for $\mathrm{C}_{14} \mathrm{H}_{24} \mathrm{INO}$ : 349.0903 ; found: 349.0907 .

## Crystal data

$\mathrm{C}_{14} \mathrm{H}_{24} \mathrm{INO}$
$M_{r}=349.24$
Orthorhombic, $P 2_{1} 2_{1} 2_{1}$
$a=10.576(2) \AA$
$b=11.049(2) \AA$
$c=12.907(3) \AA$
$V=1508.2(5) \AA^{3}$
$Z=4$
$D_{x}=1.538 \mathrm{Mg} \mathrm{m}^{-3}$

## ${ }_{2}$ INO

Orthorhombic, $P 2_{1} 2_{1} 2_{1}$
$a=10.576$ (2) A
$b=11.049$ (2) $\AA$
$V=1508.2(5) \AA^{3}$
$D_{x}=1.538 \mathrm{Mg} \mathrm{m}^{-3}$

## Mo $K \alpha$ radiation

Cell parameters from 939

## reflections

$\theta=3.1-27.7^{\circ}$
$\mu=2.11 \mathrm{~mm}^{-1}$
$T=193$ (2) K
Prism, colorless
$0.25 \times 0.22 \times 0.15 \mathrm{~mm}$

## organic papers

## Data collection

Siemens SMART/Platform CCD diffractometer
$\omega$ scans
Absorption correction: integration (SHELXTL/XPREP; Bruker, 2001)
$T_{\text {min }}=0.536, T_{\text {max }}=0.776$
14614 measured reflections

## Refinement

Refinement on $F^{2}$
$R\left[F^{2}>2 \sigma\left(F^{2}\right)\right]=0.023$
$w R\left(F^{2}\right)=0.049$
$S=1.02$
3702 reflections
155 parameters
H -atom parameters constrained $w=1 /\left[\sigma^{2}\left(F_{\mathrm{o}}{ }^{2}\right)+(0.0231 P)^{2}\right.$ $+0.2165 P$ ]
where $P=\left(F_{\mathrm{o}}{ }^{2}+2 F_{\mathrm{c}}{ }^{2}\right) / 3$

H atoms were included as riding idealized contributors $(\mathrm{C}-\mathrm{H}=$ 0.99 and $1.00 \AA$ ). $U_{\text {iso }}(\mathrm{H})$ values were assigned as 1.2 times $U_{\text {eq }}$ (carrier).

Data collection: SMART (Bruker, 2001); cell refinement: SAINT (Bruker, 2001); data reduction: SAINT; program(s) used to solve structure: SHELXTL (Bruker, 2001); program(s) used to refine structure: SHELXTL; molecular graphics: SHELXTL; software used to prepare material for publication: XCIF (Bruker, 2001).

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3702 independent reflections
3273 reflections with $I>2 \sigma(I)$
$R_{\text {int }}=0.026$
$\theta_{\text {max }}=28.3^{\circ}$
$h=-13 \rightarrow 13$
$k=-14 \rightarrow 14$
$l=-17 \rightarrow 17$
$(\Delta / \sigma)_{\text {max }}=0.002$
$\Delta \rho_{\text {max }}=0.40 \mathrm{e}_{\AA^{-3}}$
$\Delta \rho_{\min }=-0.51 \mathrm{e}^{-3}$
Extinction correction: SHELXL97
Extinction coefficient: 0.0010 (3)
Absolute structure: Flack (1983),
1569 Friedel pairs
Flack parameter: -0.015 (16)


Figure 1
SHELXTL (Bruker, 2001) plot showing 35\% probability ellipsoids for non- H atoms and circles of arbitrary size for H atoms.

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## References

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